

YOUR SIDEKICK FOR LASER OPTICS DEVELOPMENT

S1: AR<0.2% @ 1000-1060 nm, AOI=0° S2: AR<0.2% @ 1000-1060 nm, AOI=0° -0.10% @ 1000nm х $\mathbf{\hat{x}}$ 0.18% @ 1060nm Reflectance, % lγγ 800 850 900 950 1000 1050 1100 1150 1200 Wavelength, nm PO2974 Ra i8

Fig. 1.

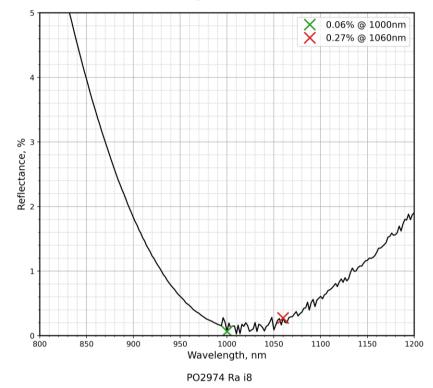
SIDE MEASURED: S1 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%



YOUR SIDEKICK FOR LASER OPTICS DEVELOPMENT

S1: AR<0.2% @ 1000-1060 nm, AOI=0° S2: AR<0.2% @ 1000-1060 nm, AOI=0°





SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: Margin of measurement error: +/-0.25%